Am29516/17 Family

16 x 16-Bit Parallel Multipliers

DISTINCTIVE CHARACTERISTICS

- High speed 16 x 16 multiplier
- Two's complement, unsigned or mixed operands
- Full product multiplexed at output
- Improved speed: 38ns clocked multiply (A devices)
 Reduced power dissipation: 2W (L devices)
- Am29516 pin and functionally compatible with TRW MPY-16HJ — Am29517 optimized for microprogramming, single clock with register enables
- TTL I/O-single +5V supply 64-pin package

GENERAL DESCRIPTION

The Am29516 and Am29517 are high speed parallel 16 x 16-bit multipliers utilizing internal ECL logic to generate a 32-bit product. 17-bit input registers are provided for the X and Y operands and their associated mode controls X_M and Y_M . These mode controls are used to specify the operands as two's complement or unsigned numbers.

At the output of the multiplier array, a format adjust control (FA), allows the user to select either a full 32-bit product or a left-shifted 31-bit product suitable for two's complement only.

Two 16-bit output registers are provided to hold the most and least significant halves of the product (MSP and LSP) as defined by FA. For asynchronous output, these registers may be made transparent by taking the feedthrough control (FT) high. A round control (RND) allows the rounding of the MSP; this control is registered, and is entered whenever either input register is clocked.

The two halves of the product may be routed to a 16-bit 3state output port (P) via a multiplexer, and in addition, the LSP is connected to the Y-input port through a separate three-state buffer.

The Am29516 X, Y, MSP and LSP registers have independent clocks (CLKX, CLKY, CLKM, CLKL). The output multiplexer control (MSPSEL) uses a pin which is a supply ground in the TRW MPY 16HJ. When this control is LOW the function is that of the MPY16HJ, thus allowing full compatibility.

The Am29517 differs in that it has a single clock input (CLK) and three register enables (ENX, ENY, ENP) for the two input registers and the entire product, respectively. This facilitates the use of the part in microprogrammed systems. In both parts data is entered into the registers on the positive edge of the clock.

The Am29516A and Am29517A are higher speed versions of the Am29516 and Am29517, respectively, offering greater than 40% speed improvement while the Am29L516 and Am29L517 low-power versions consume only one-half the power of their standard power counterparts.

BLOCK DIAGRAM Am29516/29516A/29L516 Am29517/29517A/29L517 Am29517/29S17A/29L517 Am29517/29S17A/29S17A/29L517 Am29517/29S17A/29S17A/29S17A/29L517 Am29517/29S17A/29S17A/29S17A/29L517 Am29517/29S17A/29S17A/29S17A/29S17A/29S17

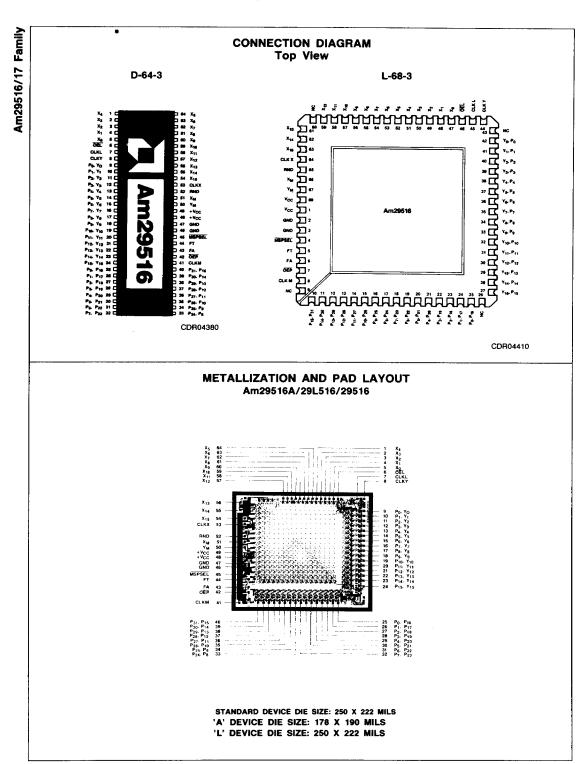
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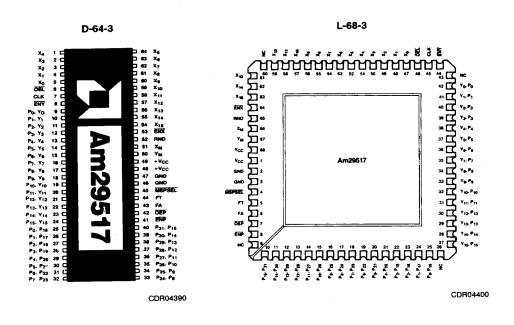
Refer to Page 13-1 for Essential Information on Military Devices

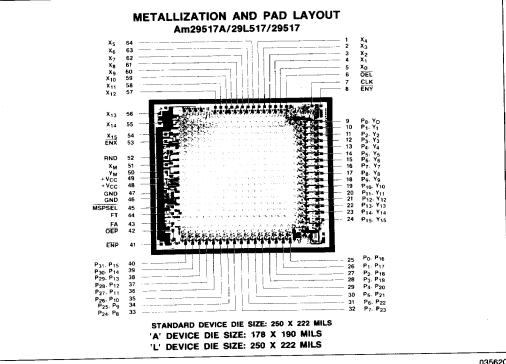
RELATED PRODUCTS

Part No.	Description
Am29501	Multi-port Pipelined Processor
Am29526/27	Sine Function Generator
Am29528/29	Cosine Function Generator
Am29520/21	Pipeline Register
Am29540	Address Generator



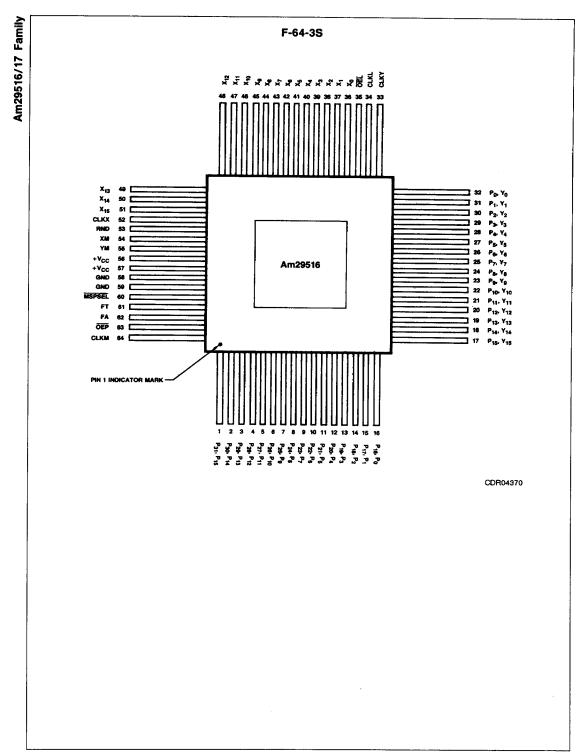
CONNECTION DIAGRAM Top View





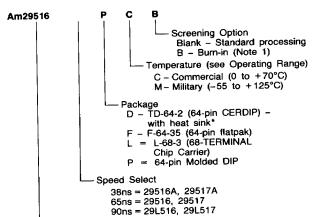
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Refer to Page 13-1 for Essential Information on Military Devices



ORDERING INFORMATION

AMD products are available in several packages and operating ranges. The order number is formed by a combination of the following: Device number, speed option (if applicable), package type, operating range and screening option (if desired).



Valid Combinations DC, DCB, DMB with heat sink Am29516 FMB. LMB without heat sink DC, DCB, DMB ~ Am29517 with heat sink Am29516A LMB -Am29517A without heat sink PC, PCB, DC, DCB, Am29L516 DM, DMB, LMB Am29L517 without heat sink

Device Type 29516, 29516

29516, 29516A 29517, 29517A 29L516, 29L517

*TD-64-1 (64-pin CERDIP) without heat sink for Low-Power versions

Note 1. 160-hour burn-in – Heat sink parts: T_A = 125°C Non-heat sink parts: T_A = 85°C

Valid Combinations

Consult the AMD sales office in your area to determine if a device is currently available in the combination you wish.

PIN	DESCRI	PTION

*Pin No.	Name	1/0	Description
1-5, 54-64	X ₀ -X ₁₅	ı	Multiplicand Data inputs.
9-24	Y ₀ -Y ₁₅ , P ₀ -P ₁₅	1/0	Multiplier Data inputs or Least Significant Product (LSP) output.
25-40	P ₁₆ -P ₃₁ , P ₀ -P ₁₅	0	MSP product port when MSPSEL is LOW. LSP product port when MSPSEL is HIGH.
51, 50	X _M ,Y _M (TCX, TCY)**	-	Mode control inputs for each data word; LOW for unsigned data and HIGH for two's complement data.
43	FA(RS)**	1	Format adjust control selects either a full 32-bit product (HIGH) or a left shifted 31-bit product with the sign bir replicated in the LSP (LOW). This control is normally high, except for certain fractional two's complement applications. (See Multiplier output formats table.)
44	FT	- 1	Feedthrough control (HIGH) makes both MSP and LSP registers transparent.
45	MSPSEL	ı	Selects either MSP (LOW) or LSP (HIGH) to be available at the product output port.
52	RND	ī	Control for rounding the MSP. Adds a binary one to the most significant bit of the LSP for two's complement and unsigned numbers.
42	OEP (TRIM)**	ı	Three-state enable for product output port.
6	OEL (TRIL)**	ı	Three-state enable for routing LSP through Y input/output port.
Am29516 O	NLY		
53, 8, 41, 7	CLKX CLKY CLKM CLKL	l	Register Clock, X ₁₅ ₋ 0, X _M , RND Register Clock, Y ₁₅ ₋ 0, Y _M , RND MSP Register Clock LSP Register Clock
Am29517 OI	NLY		
7, 53 8, 41	CLK ENX ENY ENP		Clock, All Registers Register Enable, X ₁₅₋₀ , X _M , RND Register Enable, Y ₁₅₋₀ , Y _M , RND Register Enable MSP, LSP

^{**}TRW MPY 16HJ pin designation

INPUT FORMATS (All Devices)

Fractional Two's Complement Input Format

 X_M , $Y_M = 1$

XIN 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 $-2^{0} \ 2^{-1} \ 2^{-2} \ 2^{-3} \ 2^{-4} \ 2^{-5} \ 2^{-6} \ 2^{-7} \ 2^{-8} \ 2^{-9} \ 2^{-10} \ 2^{-11} \ 2^{-12} \ 2^{-13} \ 2^{-14} \ 2^{-15}$

YIN 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 -2^{0} 2^{-1} 2^{-2} 2^{-3} 2^{-4} 2^{-5} 2^{-8} 2^{-7} 2^{-8} 2^{-9} 2^{-10} 2^{-11} 2^{-12} 2^{-13} 2^{-14} 2^{-15}

Integer Two's Complement Input Format

(Sign)

 X_M , $Y_M = 1$

(Sign)

XIN 15 14 13 12 11 10 9 8 -2^{15} 2^{14} 2^{13} 2^{12} 2^{11} 2^{10} 2^{9} 2^{8} 2^{7} 2^{6} 2^{5} 2^{4} 2^{3} 2^{2} 2^{1} 2^{0}

YIN 15 14 13 12 11 10 9 $-2^{15} \ 2^{14} \ 2^{13} \ 2^{12} \ 2^{11} \ 2^{10} \ 2^{9} \ 2^{8} \ 2^{7} \ 2^{6} \ 2^{5} \ 2^{4} \ 2^{3} \ 2^{2} \ 2^{1} \ 2^{0}$

Unsigned Fractional Input Format

 X_M , $Y_M = 0$

(Sign)

XIN 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 2-1 2-2 2-3 2-4 2-5 2-6 2-7 2-8 2-9 2-10 2-11 2-12 2-13 2-14 2-15 2-16

YIN 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 2-1 2-2 2-3 2-4 2-5 2-6 2-7 2-8 2-9 2-10 2-11 2-12 2-13 2-14 2-15 2-16

Unsigned Integer Input Format

 X_M , $Y_M = 0$

XIN 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

15 14 13 12 11 10 9 8 7 6 $2^{15} \ 2^{14} \ 2^{13} \ 2^{12} \ 2^{11} \ 2^{10} \ 2^{9} \ 2^{8} \ 2^{7} \ 2^{6} \ 2^{5} \ 2^{4} \ 2^{3} \ 2^{2} \ 2^{1} \ 2^{0} \\ \qquad 2^{15} \ 2^{14} \ 2^{13} \ 2^{12} \ 2^{11} \ 2^{10} \ 2^{9} \ 2^{8} \ 2^{7} \ 2^{6} \ 2^{5} \ 2^{4} \ 2^{3} \ 2^{2} \ 2^{1} \ 2^{0} \\ \qquad 2^{15} \ 2^{14} \ 2^{13} \ 2^{12} \ 2^{11} \ 2^{10} \ 2^{9} \ 2^{8} \ 2^{7} \ 2^{6} \ 2^{5} \ 2^{4} \ 2^{3} \ 2^{2} \ 2^{1} \ 2^{0} \\ \qquad 2^{15} \ 2^{15}$

OUTPUT FORMATS (All Devices)

Fractional 2's Complement (Shifted)* Output

FA = 0

MSP

-20 2·1 2·2 2·3 2·4 2·5 2·6 2·7 2·8 2·9 2·10 2·11 2·12 2·13 2·14 2·15

31 30 29 28 27 26 25 24 23 22 21 20 19 18 17 16

LSP

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 -2⁰ 2⁻¹⁶ 2⁻¹⁷ 2⁻¹⁸ 2⁻¹⁹ 2⁻²⁰ 2⁻²¹ 2⁻²² 2⁻²³ 2⁻²⁴ 2⁻²⁵ 2⁻²⁶ 2⁻²⁷ 2⁻²⁸ 2⁻²⁹ 2⁻³⁰ (Sign)

Fractional 2's Complement Output

FA = 1

(Sign)

MSP

															$\overline{}$
31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
-21	20	2-1	2-2	2-3	2-4	2-5	2-6	2-7	2-8	2-9	2-10	2-11	2-12	2-13	2-14
(Sig	n)														

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 $2^{-15} \, 2^{-16} \, 2^{-17} \, 2^{-18} \, 2^{-19} \, 2^{-20} \, 2^{-21} \, 2^{-22} \, 2^{-23} \, 2^{-24} \, 2^{-25} \, 2^{-26} \, 2^{-27} \, 2^{-28} \, 2^{-29} \, 2^{-30}$

LSP

Integer Two's Complement Output

FA = 1

MSP

31 30 29 28 27 26 25 24 23 22 21 20 19 18 17 16 -231230 229 228 227 226 225 224 223 222 221 220 219 218 217 216 LSP

15 14 13 12 11 10 9 8 7 6 5 4 3 2 215 214 213 212 211 210 29 28 27 26 25 24 23 22 21 20

Unsigned Fractional Output

FA = 1

(Sign)

MSP

31 30 29 28 27 26 25 24 23 22 21 20 19 18 17 16 2-1 2-2 2-3 2-4 2-5 2-6 2-7 2-8 2-9 2-10 2-11 2-12 2-13 2-14 2-15 2-16

LSP 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0 2-17 2-18 2-19 2-20 2-21 2-22 2-23 2-24 2-25 2-26 2-27 2-28 2-29 2-30 2-31 2-32

Unsigned Integer Output

FA = 1

MSP

31 30 29 28 27 26 25 24 23 22 21 20 19 18 17 16 231 230 229 228 227 226 225 224 223 222 221 220 219 218 217 216 LSP

15 14 13 12 11 10 9 8 7 6 215 214 213 212 211 210 29 28 27 26 25 24 23 22 21

*In this format an overflow occurs in the attemped multiplication of the two's complement number 1.000...(-1) with itself, yielding a product of 1.000... or -1.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature65 to +150°C	
Supply Voltage to Ground Potential	
Continuous0.5 to +7.0V	
DC Voltage Applied to Outputs For	
High Output State0.5V to +VCC max	
DC Input Voltage0.5 to +5.5V	
DC Output Current, Into Outputs	
DC Input Current -30 to +5 0m4	

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices Temperature	
DIPs	
Chip Carriers	T _C = 0°C to 85°C
Supply Voltage	
Military (M) Devices	
Temperature	55°C to +125°C
Supply Voltage	
Operating ranges define those lim ality of the device is guaranteed.	its over which the function-

DC CHARACTERISTICS over operating range unless otherwise specified Am29516/29517

Parameters	Description		Min	Typ (Note 1)	Max	Units		
V _{OH}	Output HiGH Voltage	V _{CC} = MIN V _{IN} = V _{IH} or V _{IL}		I _{OH} = -0.4mA	2.4	2.7		Volts
VOL	Output LOW Voltage	V _{CC} = MIN V _{IN} = V _{IH} or V _{IL}					.5	Volts
V _{IH}	Input HIGH Level	Guaranteed input	logical HIGH	roltage for all inputs	2.0	<u> </u>		Volts
VIL	Input LOW Level	Guaranteed input	logical LOW v	oltage for all inputs	_	<u> </u>	.8	Volts
VI	input Clamp Voltage	V _{CC} = MIN, I _{IN} = -	V _{CC} = MIN, I _{IN} = -18mA					Volts
lıL.	Input LOW Current	V _{CC} = MAX, V _{IN} =	_		-1.5 -0.4	mA		
ин	Input HIGH Current	V _{CC} = MAX, V _{IN} =			75	μА		
lj .	Input HIGH Current	V _{CC} = MAX, V _{IN} =	5.5V			<u> </u>	1	mA.
lozн	Off State (High Impedance)	V _{CC} = MAX	Product	V _O = 2.4V			25	
lozi	Output Current	1 100 - 11170	Fioddci	V _O = 0.4V		\vdash	-25	μΑ
Isc	Output Short Circuit Current (Note 2)	V _{CC} = MAX	Y, Product	V _O = 0V	-3		-30	mA
			T _A = + 25°	0		600		· · · · · · · · · · · · · · · · · · ·
		COM'L Devices	T _A = 0 to	+ 70°C (Note 4)			800	
lcc	Power Supply Current	V _{CC} = MAX	$T_A = +70^{\circ}$	C (Note 4)			750	mA
	(Note 3)	MIL Devices T _A = -55 to +125°C					900	
		V _{CC} = MAX	$T_A = +125$	°C			800	

Notes: 1. Typical limits are at V_{CC} = 5.0V, +25°C ambient and maximum loading.

2. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

3. OEF and OEL LOW with all product (MSP and LSP) bits LOW.

4. Chip Carriers: T_C = 85°C.

DC CHARACTERISTICS over operating range unless otherwise specified Am29516A/29L516/Am29517A/29L517

Parameters	Description		Test Conditions		Min	Typ (Note 1)	Max	Units
/он	Output High Voltage	V _{CC} = MIN V _{IN} = V _{IH} or V _{IL}	I _{OH} = -0.4	4mA	2.4	2.7		Volts
/OL	Output LOW Voltage	V _{CC} = MiN V _{IN} = V _{IH} or V _{II}	I _{OL} = 4.0n		<u></u>	.3	.5	Volts
	Input HIGH Level	Guaranteed input	ogical HIGH voltage for	all inputs	2.0			Volts
IH	Input LOW Level	Guaranteed input	ogical LOW voltage for	all inputs		↓	.8	Volts
iL	Input Clamp Voltage	VCC = MIN, IIN = -				↓	- 1.5	Voit
<u>′ı</u>	Input LOW Current	V _{CC} = MAX, V _{IN} =				↓	-0.4	mA
L	Input HIGH Current	VCC = MAX, VIN =			<u> </u>		75	μΑ
н	Input HIGH Current		V _{CC} = MAX, V _{IN} = 5.5V				1_1_	mA
<u> </u>	<u> </u>			$V_0 = 2.4V$			25	μА
OZH	Off State (High Impedance) Output Current	V _{CC} = MAX	Product	V _O = 0.4V			-25	+-
ozl	Output Short Circuit Current	V _{CC} = MAX	Y, Product	Vo = 0V	-3		-30	mA
	(Note 2)		 	A Devices		600		_
			T _A = +25°C	L Devices		300		_
			T _A = 0 to +70°C	A Devices			800	╛
		COM'L Devices	(Note 4)	L Devices		<u></u>	400	
		V _{CC} = MAX	<u> </u>	A Devices		L	750	mA.
loc	Power Supply Current		T _A = +70°C (Note 4)	L Devices			350	J ""
(Note 3)			 	A Devices			900	4
	1	T _C = -55 to + 125°C	L Devices		I	440	_	
	MIL Devices VCC = MAX		A Devices			800	╛	
		1 *66 .****	T _{CC} = + 125°C	L Devices			350	

Notes: 1. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

2. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

3. OEP and OEL LOW with all product (MSP and LSP) bits LOW.

4. Chip Carriers: T_C = 85°C.

SWITCHING CHARACTERISTICS over operating range unless otherwise specified (Note 1) Am29516/29517

					COMM	ERCIAL	MILIT	MILITARY	
D	Description		Test Conditions	Тур	Min	Max	Min	Max	Units
Parameters	Unclocked Multiply Ti			50		85	I	95	ns
tmuc		Clocked Multiply Time		40		(65)		75	ns
tMC	Xi, Yi, RND Set-up T		i	10	20		25		ns
ts				0	3		3		ns
tH	Xi, Yi, RND Hold Tin		Load 1	10	15		15		ns
tpwH	Clock Pulse Width H		Loud	10	15		15		ns
tpwl	Clock Pulse Width L			20		30		35	ns
1PDSEL	MSPSEL to Product Out	Out		20		30		35	ns
tPDP	Output Clock to P		ļ	20		30	— —	35	ns.
tpDY	Output Clock to Y		ļ	12		23		28	ns
tpHZ	OFP Disable Time	High to Z	4	15	 	23	 	28	ns
tpLZ	OEP Disable Tille	Low to Z	_	25	 	32	 	35	ns
^t PZH	T == 0 11 T	Z to High	1		ļ	32	+	35	ns
tPZL	OEP Enable Time	Z to Low	Load 2	25	<u> </u>	23	 	28	ns
tpHZ		High to Z	2000 2	12	1	23	+	28	ns
telZ	OEL Disable Time	Low to Z]	15		32	 	35	ns
tpzH		Z to High		25	↓	32	+	35	ns
tPZL	OEL Enable Time	Z to Low	L	25	↓	32	+	 _	+
ts	Clock Enable Set-up (Am29517 Only)	Clock Enable Set-up Time (Am29517 Only)		5	10		15	1	ns
tH	Clock Enable Hold Time (Am29517 Only)		Load 1	0	3		3	ļ	ns
thcl	Clock Low Hold Tin Relative to CLKML (Am29516 Only)	ne CLKXY (See Note 2)		0	0	th 200 Lf/min	0	1 1-11-1	ns

Notes: 1. Switching Characteristics are measured and guaranteed for T_A as specified with 200 Lf/min flowing across the device.

2. To ensure that the correct product is entered in the output registers, new data may not be entered into the input registers before the output registers have been clocked.

SWITCHING CHARACTERISTICS over operating range unless otherwise specified (Note 1) Am29L516/29L517

			Test		COMM	IERCIAL	MILITARY*		
Parameters	Descrip	tion	Conditions	Тур	Min	Max	Min	Max	Units
t _{MUC}	Unclocked Multiply	Гime		90		120	1	135	ns
tMC	Clocked Multiply Tim	ne	1	70		90		(100)	ns
ts	Xi, Yi, RND Set-up	Time			25		25		ns
tн	X _i , Y _i , Hold Time			0		0		ns	
tH	RND Hold Time	RND Hold Time			3		3		ns
^t PWH	Clock Pulse Width I	tigh	Load 1		20		20		ns
tpwL	Clock Pulse Width L	.ow]		20		20		ns
†PDSEL	MSPSEL to Product	Out	7	25		35	1	40	ns
tPDP	Output Clock to P			25		35	1	40	ns
tPDY	Output Clock to Y			25		35		40	ns
t _{PHZ}		High to Z		20		30		35	ns
t _{PLZ}	OEP Disable Time	Low to Z		.20		30		35	ns
^t PZH		Z to High		25		35		40	ns
tPZL	OEP Enable Time	Z to Low		25		35		40	ns
t _{PHZ}		High to Z	Load 2	20		30		35	ns
tPLZ	OEL Disable Time	Low to Z		20		30		35	ns
^t PZH		Z to High		25		35		40	ns
t _{PZL}	OEL Enable Time	Z to Low		25		35		40	ns
ts	Clock Enable Set-up (Am29L517 Only)	Clock Enable Hold Time (Am29L517 Only) Clock Low Hold Time CLKXY Relative to CLKML (See Note 2)		10	15		20		ns
tн					3		5		ns
†HCL					0		0		ns

Notes: 1. Switching Characteristics are measured and guaranteed for T_A as specified with 200 Lf/min flowing across the device.

2. To ensure that the correct product is entered in the output registers, new data may not be entered into the input registers before the output registers have been clocked.

*PRELIMINARY

SWITCHING CHARACTERISTICS over operating range unless otherwise specified (Note 1) Am29516A/517A

		T	,	COMME	RCIAL	MILIT	TARY	_
Parameters	Description	Test Conditions	Тур	Min	Max	Min	Max	Units
MUC	Unclocked Multiply Time		45		58	<u> </u>	65	ns
tMC	Clocked Multiply Time]	30	└	38	<u> </u>	444	ns ns
ts	X _i , Y _i , Set-up Time)	4	7	└── ─	B	 	ns
<u>ч</u>	X _i , Y _i , Hold Time] '	11	3	 '		-	ns
ts	RND Set-up Time] 1	4	7			1	ns
t _H	RND Hold Time	Load 1	1	3		<u>а</u>	Afric.	ns
tpwH	Clock Pulse Width High		7	7	1 1	3	+	ns
tpwi	Clock Pulse Width Low		7	3		A	21	ns
1PDSEL	MSPSEL to Product Out		13	A TOTAL	18 20		23	ns
tPDP	Output Clock to P			A	9.50	 	23	ns
teny	Output Clock to Y		A 184		20	 	17	ns
tpHZ	High to Z		A TOP I	A	15	 	17	ns
1PLZ	OEP Disable Time Low to Z		19		15	 	25	ns
tezh	Z to thigh		20	 _	23	+	25	ns
tpzL	OEP Enable Time	and 2	15		15	+	17	ns
tpHZ	Ach tel	- NOTO 2	13	1	15	 	17	ns
tpLZ	OEL Disable Time Low to		12	↓	23	+	25	ns
tpzH	Z to High	_	20	+	23	+	25	ns
tpzL	OEL Example Time Z to Low		15	 	+	+	+	+
ts	Clock Enable Set-up Time (Am29517A Only)			10		15	 	ns
tн	Clock Enable Hold Time (Am29517A Only)	Load 1		3	<u> </u>	3		ns
tHCL	Clock Low Hold Time CLKXY Relative to CLKML (See Note 2 (Am29516A Only)		-1			<u></u>	devices	ns

Notes: 1. Switching Characteristics are measured and guaranteed for TA as specified with 200 Lf/min flowing across the device.

2. To ensure that the correct product is entered in the output registers, new data may not be entered into the input registers before

the output registers have been clocked.

Notes on Testing

Incoming test procedures on this device should be carefully planned, taking into account the high complexity and power levels of the part. The following notes may be useful:

- 1. Insure the part is adequately decoupled at the test head. Large changes in VCC current as the device switches may cause erroneous function failures due to VCC changes.
- 2. Do not leave inputs floating during any tests, as they may start to oscillate at high frequency.
- 3. Do not attempt to perform threshold tests at high speed. Following an input transition, ground current may change by as much as 400mA in 5-8ns. Inductance in the ground

- cable may allow the ground pin at the device to rise by 100s of millivolts momentarily.
- 4. Use extreme care in defining input levels for AC tests. Many inputs may be changed at once, so there will be significant noise at the device pins and they may not actually reach VIL or VIH until the noise has settled. AMD recommends using $V_{IL} \le 0.0V$ and $V_{IH} \ge 3.0V$ for AC tests.
- 5. To simplify failure analysis, programs should be designed to perform DC, Function, and AC tests as three distinct groups of tests.
- 6. To assist in testing, AMD offers complete documentation on our test procedures and, in most cases, can provide Fairchild Sentry programs under license.

SWITCHING TEST CIRCUIT Normal Load (Load 1) Three-State Delay Load (Load 2) TO OUTPUT O OUT

TEST WAVEFORMS

TCR01250

(All Devices)

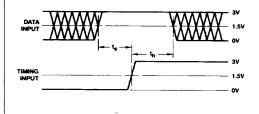
Test	V _X	Output Waveform - Measurement Level
All t _{PD} s	Vcc	V _{OH}
t _{PHZ}	0.0V	VOH 0.5V
t _{PLZ}	2.6V	V _{OL}
t _{PZH}	0.0V	0.0VVOH
^t PZL	2.6V	2.6V

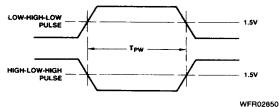
WFR02780

TCR01260

SETUP AND HOLD TIME (All Devices)

PULSE WIDTH (All Devices)

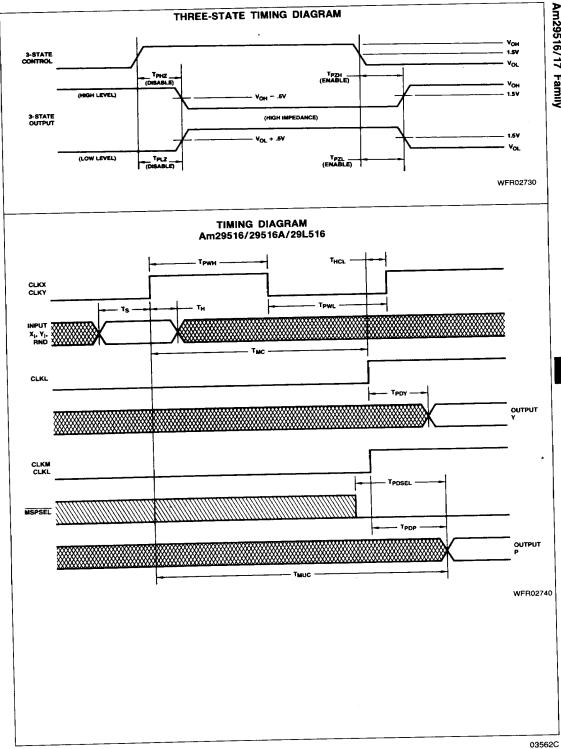


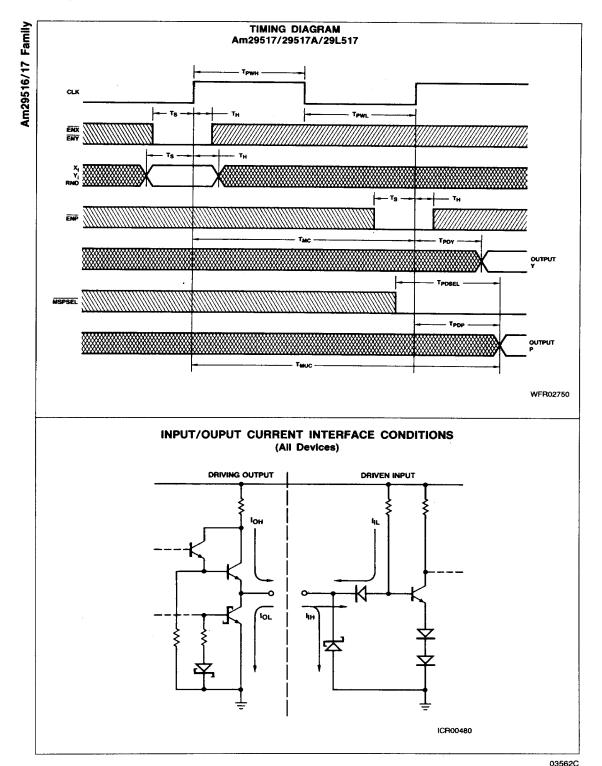


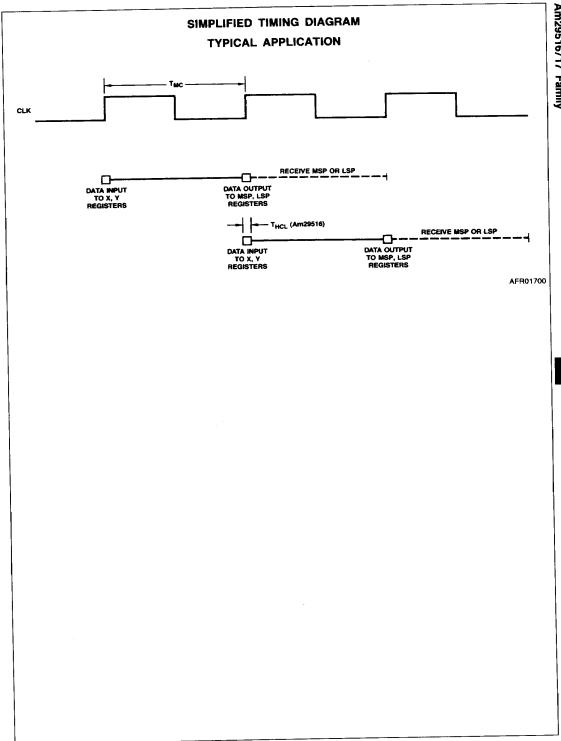
WFR02970

Notes: 1. Diagram shown for HIGH data only. Output transition may be opposite sense.

2. Cross hatched area is don't care condition.







03562C Refer to Page 13-1 for Essential Information on Military Devices

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